

<b>Notice of References Cited</b>	Application/Control No. 10/575,858		Applicant(s)/Patent Under Reexamination LEE, SANG RYUL	
	Examiner Quang T. Van		Art Unit 3742	Page 1 of 1

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*	A	US-2004/0182856	09-2004	Lee et al.	219/739
*	B	US-6,521,875	02-2003	Kim et al.	219/715
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